

# MT4410

## N-Channel PowerTrench<sup>®</sup> MOSFET 30V, 18A, 4.5mΩ



**MT Semiconductor<sup>®</sup>**

<http://www.mtsemi.com>

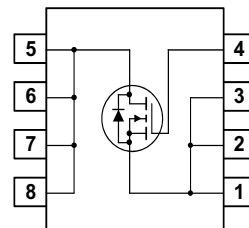
### General Description

This N-Channel MOSFET has been designed specially to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers. It has been optimized for low gate charge, low  $R_{DS(on)}$  and fast switching speed.

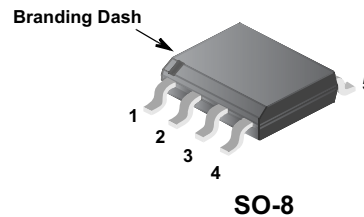
### Features

- $R_{DS(on)} = 4.5m\Omega$ ,  $V_{GS} = 10V$ ,  $I_D = 18A$
- $R_{DS(on)} = 6.5m\Omega$ ,  $V_{GS} = 4.5V$ ,  $I_D = 17A$
- Low gate charge
- High performance trench technology for extremely low  $R_{DS(ON)}$
- High power and current handling capability
- RoHS compliant

### Simplified Schematic



### MARKING DIAGRAM & PIN ASSIGNMENT



### Absolute Maximum Ratings ( $T_A = 25^\circ C$ unless otherwise noted)

Symbol	Parameter	Ratings	Units
$V_{DSS}$	Drain to Source Voltage	30	V
$V_{GS}$	Gate to Source Voltage	$\pm 20$	V
$I_D$	Drain Current		
	Continuous ( $T_A = 25^\circ C$ , $V_{GS} = 10V$ , $R_{\theta JA} = 50^\circ C/W$ )	18	A
	Continuous ( $T_A = 25^\circ C$ , $V_{GS} = 4.5V$ , $R_{\theta JA} = 50^\circ C/W$ )	17	A
	Pulsed	134	A
$E_{AS}$	Single Pulse Avalanche Energy (Note 1)	420	mJ
$P_D$	Power dissipation	2.5	W
	Derate above $25^\circ C$	20	mW/ $^\circ C$
$T_J, T_{STG}$	Operating and Storage Temperature	-55 to 150	$^\circ C$

### Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance, Junction to Case (Note 2)	25	$^\circ C/W$
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 2a)	50	$^\circ C/W$
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 2b)	125	$^\circ C/W$

### Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
MT4410	MT4410	SO-8	330mm	12mm	2500 units

## Package Marking and Ordering Information

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MT4410	MT4410	SO-8	330mm	12mm	2500 units

## Electrical Characteristics $T_J = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
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### Off Characteristics

$V_{DSS}$	Drain to Source Breakdown Voltage	$I_D = 250\mu\text{A}$ , $V_{GS} = 0\text{V}$	30	-	-	V
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS} = 24\text{V}$ $V_{GS} = 0\text{V}$ $T_J = 150^\circ\text{C}$	-	-	1	$\mu\text{A}$
$I_{GSS}$	Gate to Source Leakage Current	$V_{GS} = \pm 20\text{V}$	-	-	$\pm 100$	nA

### On Characteristics

$V_{GS(TH)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}$ , $I_D = 250\mu\text{A}$	1.2	-	2.5	V
$r_{DS(on)}$	Drain to Source On Resistance	$I_D = 18\text{A}$ , $V_{GS} = 10\text{V}$	-	4.5	6.0	$m\Omega$
		$I_D = 17\text{A}$ , $V_{GS} = 4.5\text{V}$	-	6.5	9.0	
		$I_D = 18\text{A}$ , $V_{GS} = 10\text{V}$ , $T_J = 150^\circ\text{C}$	-	5.5	7.2	

### Dynamic Characteristics

$C_{ISS}$	Input Capacitance	$V_{DS} = 15\text{V}$ , $V_{GS} = 0\text{V}$ , $f = 1\text{MHz}$	-	1615	-	pF	
$C_{OSS}$	Output Capacitance		-	500	-	pF	
$C_{RSS}$	Reverse Transfer Capacitance		-	150	-	pF	
$R_G$	Gate Resistance	$V_{GS} = 0.5\text{V}$ , $f = 1\text{MHz}$	0.5	2.0	3.5	$\Omega$	
$Q_{g(TOT)}$	Total Gate Charge at 10V	$V_{GS} = 0\text{V}$ to 10V	$V_{DD} = 15\text{V}$ $I_D = 18\text{A}$ $I_g = 1.0\text{mA}$	-	85	112	nC
$Q_{g(5)}$	Total Gate Charge at 5V	$V_{GS} = 0\text{V}$ to 5V		-	45	62	nC
$Q_{g(TH)}$	Threshold Gate Charge	$V_{GS} = 0\text{V}$ to 1V		-	4.6	6.0	nC
$Q_{gs}$	Gate to Source Gate Charge			-	11	-	nC
$Q_{gs2}$	Gate Charge Threshold to Plateau			-	6.4	-	nC
$Q_{gd}$	Gate to Drain "Miller" Charge			-	15	-	nC

### Switching Characteristics ( $V_{GS} = 10\text{V}$ )

$t_{ON}$	Turn-On Time	$V_{DD} = 15\text{V}$ , $I_D = 18\text{A}$ $V_{GS} = 10\text{V}$ , $R_{GS} = 3.3\Omega$	-	-	8.6	ns
$t_{d(ON)}$	Turn-On Delay Time		-	9	-	ns
$t_r$	Rise Time		-	8.4	-	ns
$t_{d(OFF)}$	Turn-Off Delay Time		-	16	-	ns
$t_f$	Fall Time		-	21	-	ns
$t_{OFF}$	Turn-Off Time		-	-	12.2	ns

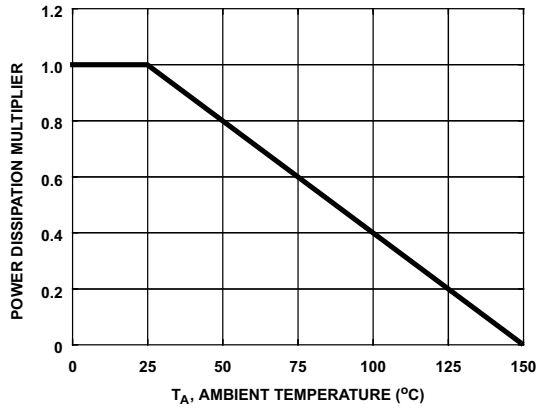
### Drain-Source Diode Characteristics

$V_{SD}$	Source to Drain Diode Voltage	$I_{SD} = 18\text{A}$	-	-	1.25	V
		$I_{SD} = 2.1\text{A}$	-	-	1.0	V
$t_{rr}$	Reverse Recovery Time	$I_{SD} = 18\text{A}$ , $dI_{SD}/dt = 100\text{A}/\mu\text{s}$	-	-	37	ns
$Q_{RR}$	Reverse Recovered Charge	$I_{SD} = 18\text{A}$ , $dI_{SD}/dt = 100\text{A}/\mu\text{s}$	-	-	22	nC

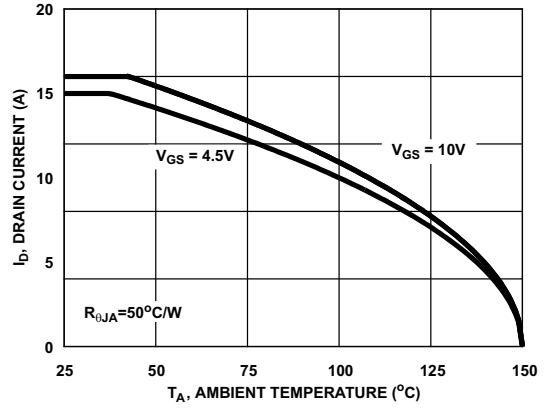
#### Notes:

- Starting  $T_J = 25^\circ\text{C}$ ,  $L = 1\text{mH}$ ,  $I_{AS} = 29\text{A}$ ,  $V_{DD} = 30\text{V}$ ,  $V_{GS} = 10\text{V}$ .
- $R_{\theta JA}$  is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins.  $R_{\theta JC}$  is guaranteed by design while  $R_{\theta JA}$  is determined by the user's board design.
  - $50^\circ\text{C}/\text{W}$  when mounted on a  $1\text{in}^2$  pad of 2 oz copper.
  - $125^\circ\text{C}/\text{W}$  when mounted on a minimum pad.

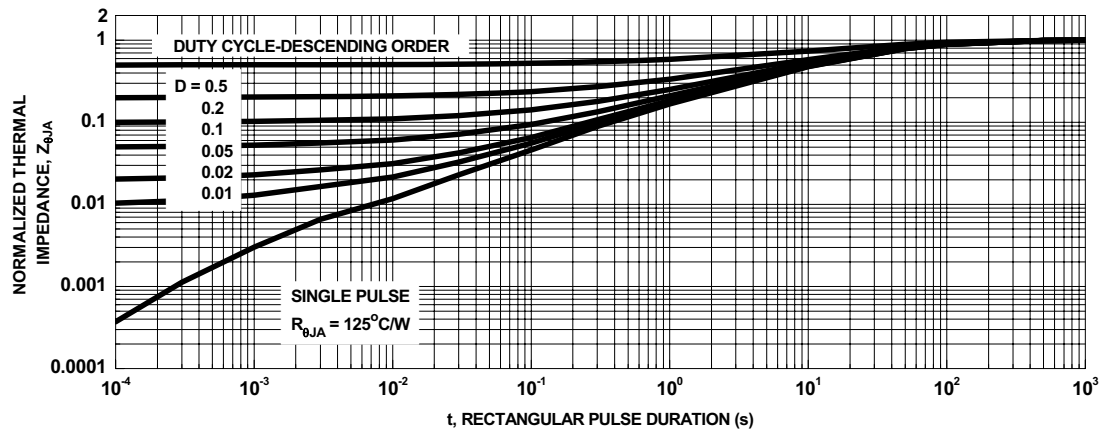
**Typical Characteristics**  $T_J = 25^\circ\text{C}$  unless otherwise noted



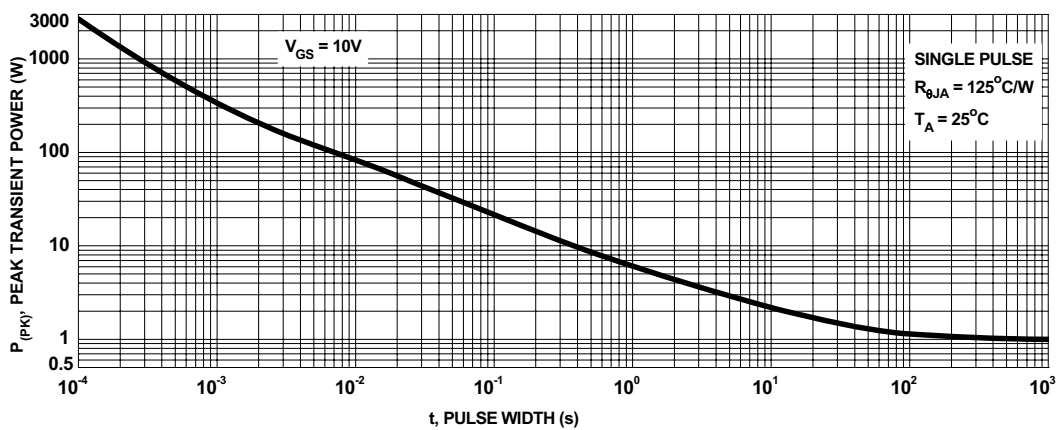
**Figure 1. Normalized Power Dissipation vs Ambient Temperature**



**Figure 2. Maximum Continuous Drain Current vs Ambient Temperature**

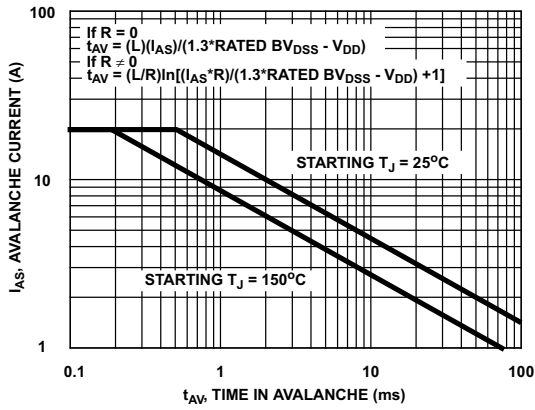


**Figure 3. Normalized Maximum Transient Thermal Impedance**

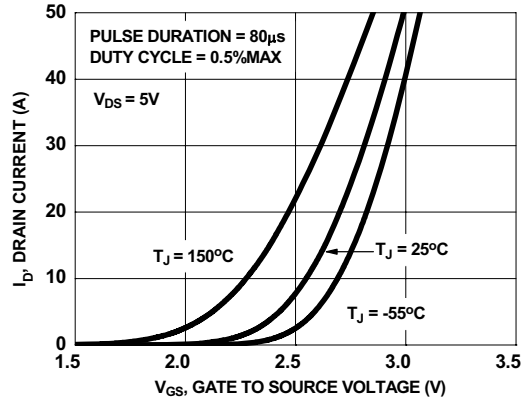


**Figure 4. Single Pulse Maximum Power Dissipation**

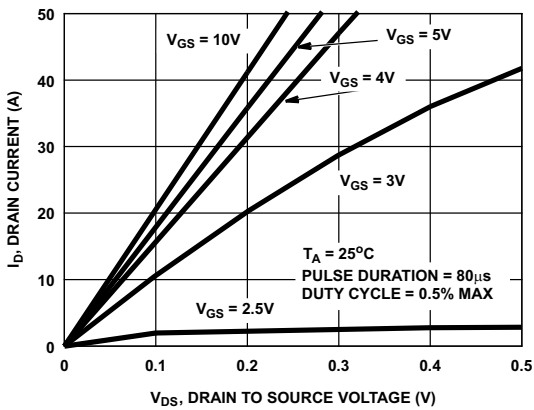
**Typical Characteristics**  $T_J = 25^\circ\text{C}$  unless otherwise noted



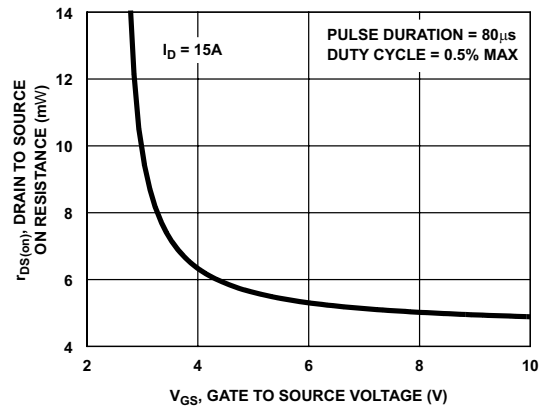
NOTE: Refer to Fairchild Application Notes AN7514 and AN7515  
**Figure 5. Unclamped Inductive Switching Capability**



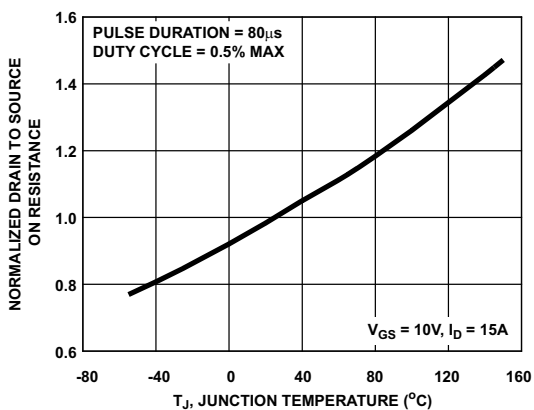
**Figure 6. Transfer Characteristics**



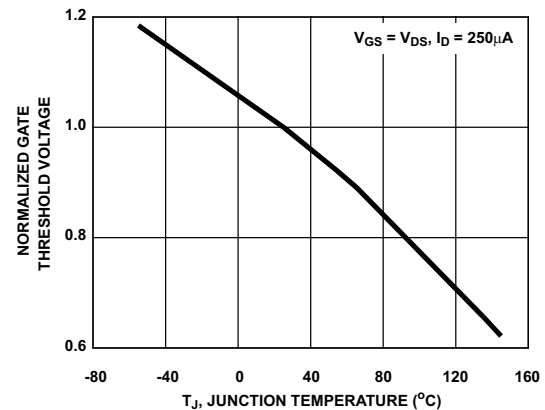
**Figure 7. Saturation Characteristics**



**Figure 8. Drain to Source On Resistance vs Gate Voltage and Drain Current**

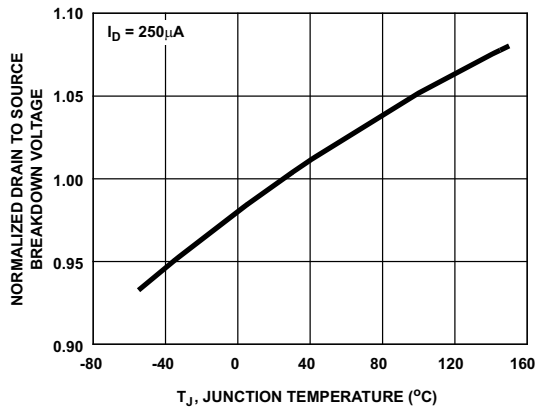


**Figure 9. Normalized Drain to Source On Resistance vs Junction Temperature**

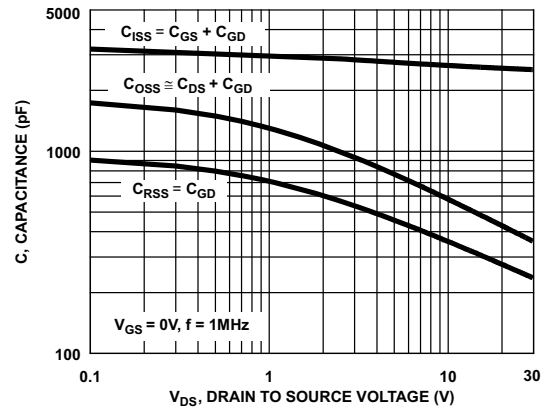


**Figure 10. Normalized Gate Threshold Voltage vs Junction Temperature**

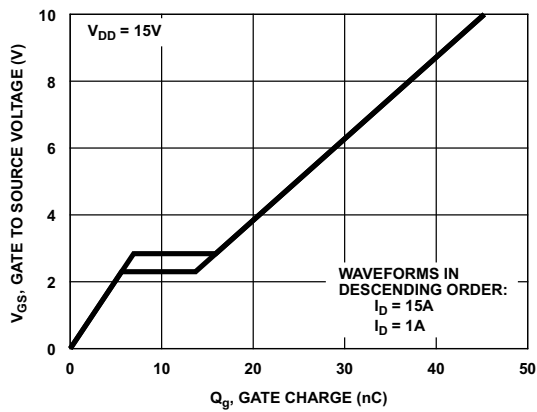
**Typical Characteristics**  $T_J = 25^\circ\text{C}$  unless otherwise noted



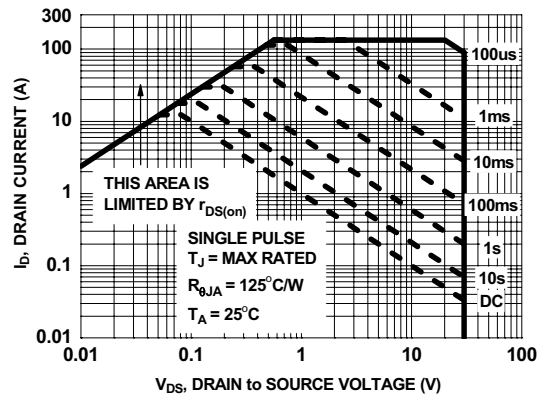
**Figure 11. Normalized Drain to Source Breakdown Voltage vs Junction Temperature**



**Figure 12. Capacitance vs Drain to Source Voltage**

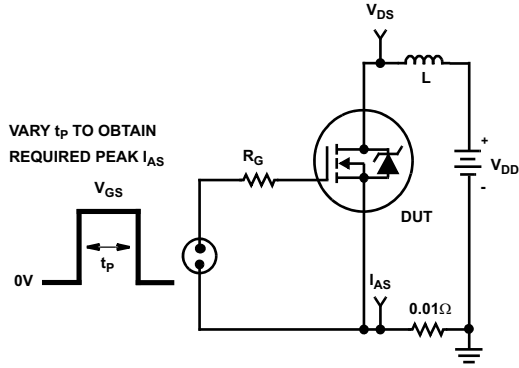


**Figure 13. Gate Charge Waveforms for Constant Gate Currents**

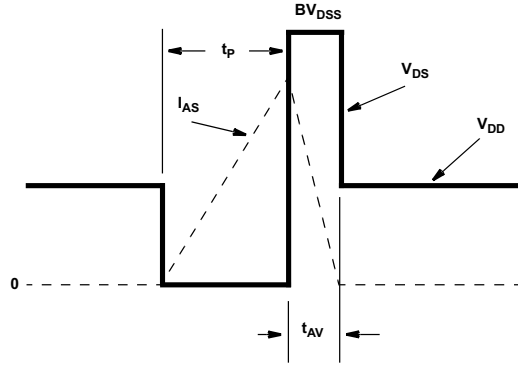


**Figure 14. Forward Bias Safe Operating Area**

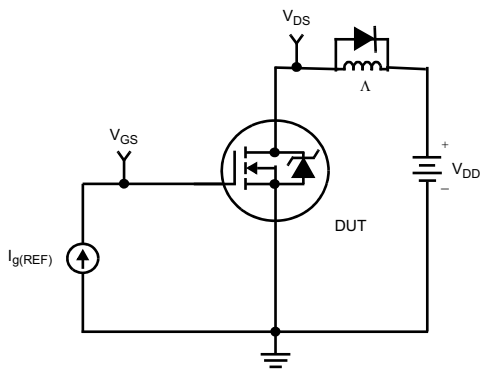
**Test Circuits and Waveforms**



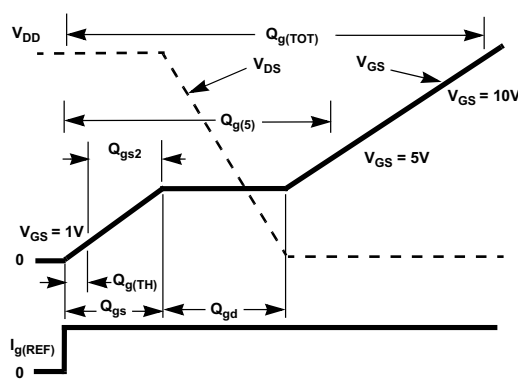
**Figure 15. Unclamped Energy Test Circuit**



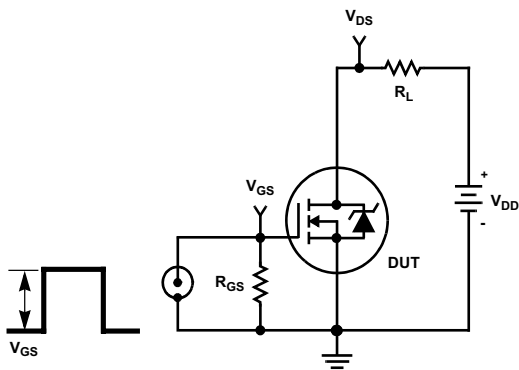
**Figure 16. Unclamped Energy Waveforms**



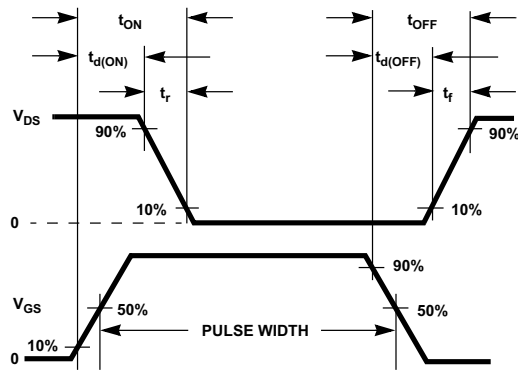
**Figure 17. Gate Charge Test Circuit**



**Figure 18. Gate Charge Waveforms**



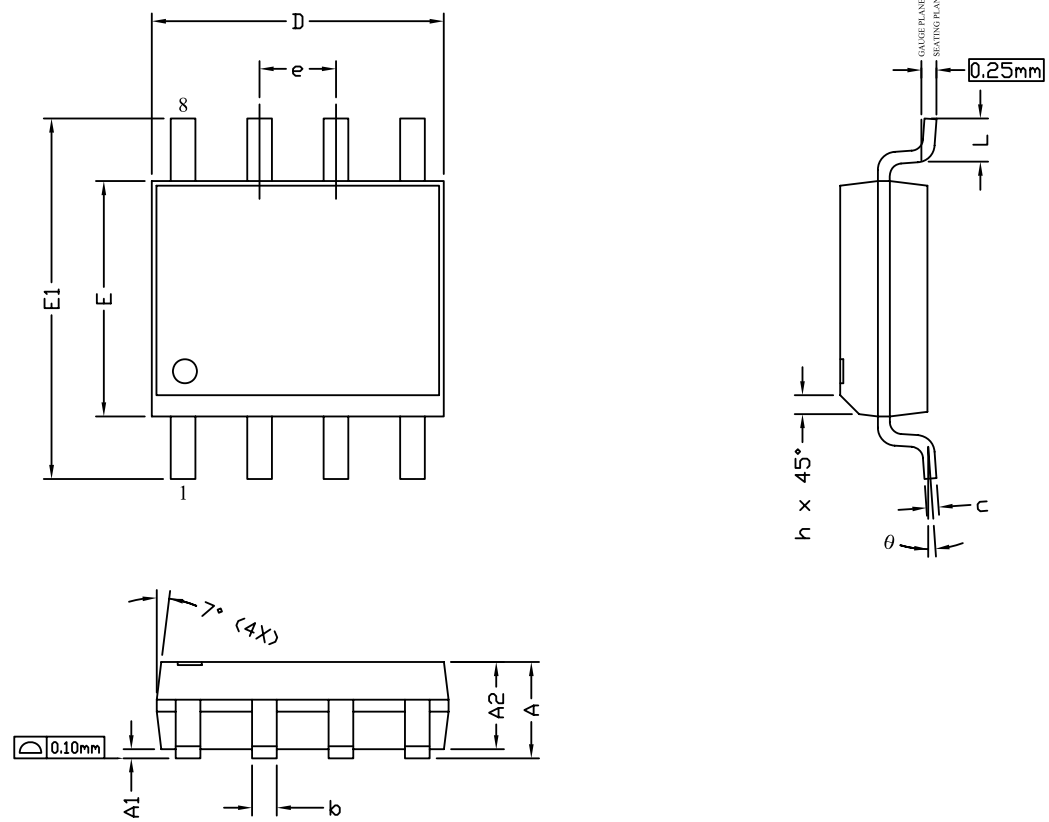
**Figure 19. Switching Time Test Circuit**



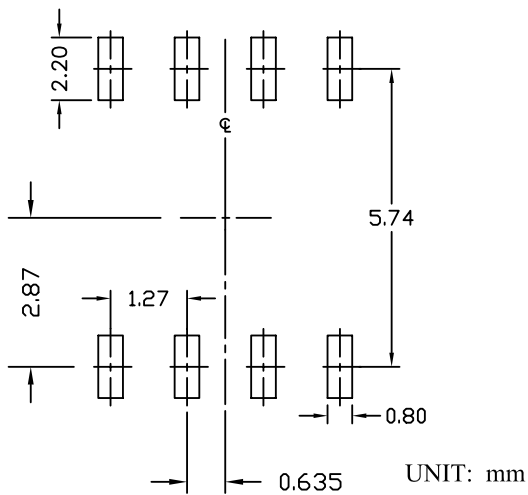
**Figure 20. Switching Time Waveforms**

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Version	rev H

S08 PACKAGE OUTLINE



RECOMMENDED LAND PATTERN



SYMBOLS	DIMENSIONS IN MILLIMETERS			DIMENSIONS IN INCHES		
	MIN	NOM	MAX	MIN	NOM	MAX
A	1.35	1.65	1.75	0.053	0.065	0.069
A1	0.10	---	0.25	0.004	---	0.010
A2	1.25	1.50	1.65	0.049	0.059	0.065
b	0.31	---	0.51	0.012	---	0.020
c	0.17	---	0.25	0.007	---	0.010
D	4.80	4.90	5.00	0.189	0.193	0.197
E	3.80	3.90	4.00	0.150	0.154	0.157
e	1.27 BSC			0.050 BSC		
E1	5.80	6.00	6.20	0.228	0.236	0.244
h	0.25	---	0.50	0.010	---	0.020
L	0.40	---	1.27	0.016	---	0.050
θ	0°	---	8°	0°	---	8°

NOTE

1. ALL DIMENSIONS ARE IN MILLIMETERS.
2. DIMENSIONS ARE INCLUSIVE OF PLATING.
3. PACKAGE BODY SIZES EXCLUDE MOLD FLASH AND GATE BURRS.  
MOLD FLASH AT THE NON-LEAD SIDES SHOULD BE LESS THAN 6 MILS EACH.
4. DIMENSION L IS MEASURED IN GAUGE PLANE.
5. CONTROLLING DIMENSION IS MILLIMETER.  
CONVERTED INCH DIMENSIONS ARE NOT NECESSARILY EXACT.

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### Keep safety first in your circuit designs!

1. MOS-TECH Semiconductor Corp. puts the maximum effort into making semiconductor products better and more reliable, but there is always the possibility that trouble may occur with them. Trouble with semiconductors may lead to personal injury, fire or property damage. Remember to give due consideration to safety when making your circuit designs, with appropriate measures such as (i) placement of substitutive, auxiliary circuits, (ii) use of nonflammable material or (iii) prevention against any malfunction or mishap.